

IGBT4 Low Power Chip

Features:

- 1200V Trench + Field stop technology
- low switching losses
- positive temperature coefficient
- easy paralleling

This chip is used for:

• low/medium power modules

• low/medium power drives



Chip Type	V_{CE}	I Cn	Die Size	Package
IGC13T120T6L	1200V	10A	3.54 x 3.81 mm ²	sawn on foil

Applications:

MECHANICAL PARAMETER

Raster size	3.54 x 3.81		
Emitter pad size	1.497 x 2.34	mm ²	
Gate pad size	0.608 x 1.092		
Area total / active	13.48 / 6.93		
Thickness	115	μm	
Wafersize	150	mm	
Flat position	90	grd	
Max.possible chips per wafer	1109		
Passivation frontside	Photoimide		
Pad metal	3200 nm AlSiCu		
Backside metal	Ni Ag –system suitable for epoxy and soft solder die bonding		
Die bond	Electrically conductive glue or solder		
Wire bond	Al, <500µm		
Reject ink dot size	Ø 0.65mm ; max 1.2mm		
Recommended storage environment	Store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C		



MAXIMUM RATINGS

Parameter	Symbol	Value	Unit	
Collector-Emitter volta ge, Tj=25 °C	V _{CE}	1200	V	
DC collector current, limited by T _{jmax}	I _C	1)	А	
Pulsed collector current, t_p limited by T_{jmax}	I _{cpuls}	30	A	
Gate-Emitter voltage	V _{GE}	±20	V	
Operating junction temperature	T _j	-40 +175	°C	
Short circuit data 2 V $_{GE}$ = 15V, V $_{CC}$ = 800V, Tvj = 150°C	tp	10	μs	
Reverse bias safe operating area ²) (RBSOA)	I _{C max} = 20A, V _{CE max} = 1200V, Tvj max= 150°C			

¹⁾ depending on thermal properties of assembly

²⁾ not subject to production test - verified by design/characterization

STATIC CHARACTERISTICS (tested on wafer), T_j =25 °C

Parameter	Symbol	Conditions	Value			Unit
		Conditions	min.	typ.	max.	
Collector-Emitter breakdown voltage	V _{(BR)CES}	$V_{GE}{=}0V$, $I_{C}{=}$ 0.5 m A	1200			
Collector-Emitter saturation voltage	V _{CE(sat)}	V_{GE} =15V, I _C =10A	1.6	1.85	2.1	V
Gate-Emitter threshold voltage	V _{GE(th)}	$I_C=0.35mA$, $V_{GE}=V_{CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	$V_{CE} = 1200 V$, $V_{GE} = 0 V$			1.2	μA
Gate-Emitter leakage current	I _{GES}	$V_{CE}=0V$, $V_{GE}=20V$			120	nA
Integrated gate resistor	R _{Gint}			-		Ω

ELECTRICAL CHARACTERISTICS (not subject to production test - verified by design/characterization)

Parameter	Symbol	Conditions	Value			Unit
i arameter	Gymbol	Conditions	min.	typ.	max.	Onic
Input capacitance	Ciss	$V_{CE}=25V$,		625		
Output capacitance	Coss	$V_{GE} = 0 V$,		60		рF
Reverse transfer capacitance	Crss	f=1MHz		40		



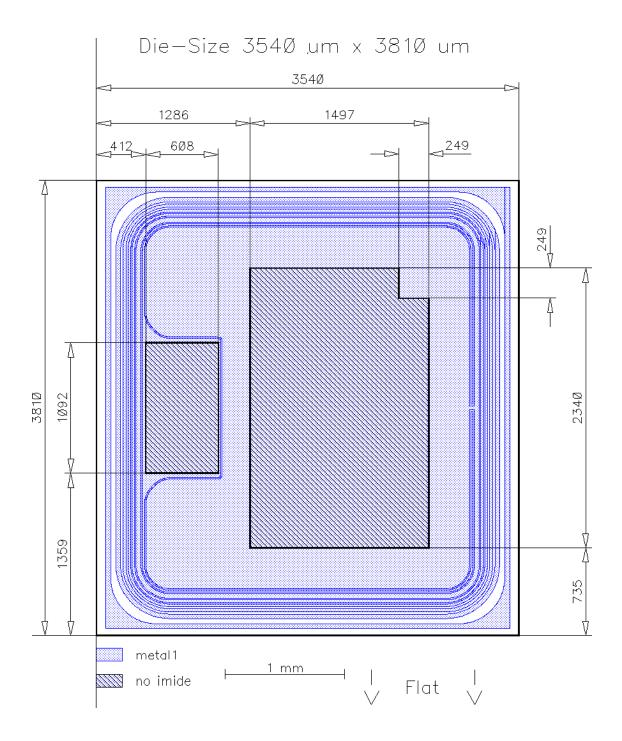
SWITCHING CHARACTERISTICS inductive load (not subject to production test - verified by design /characterization)

Parameter	Symbol	Conditions ¹⁾	Value			Unit
Faranielei	Symbol		min.	typ.	max.	Onit
Turn-on delay time	t _{d(on)}	$T_j = 125^{\circ}C$ $V_{CC} = 600V$, $I_C = 10 A$, $V_{GE} = -15/15V$,		tbd		
Rise time	t _r			tbd		ns
Turn-off delay time	t _{d(off)}			tbd		113
Fall time	t _f	R _G =Ω		tbd		

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING



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FURTHER ELECTRICAL CHARACTERISTICS

This chip data sheet refers to the device data sheet	tbd	
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DESCRIPTION

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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